Application/Control No.	Applicant(s)/Patent under Reexamination	
10/524,792	KOIKE ET AL.	
Examiner	Art Unit	
Jason R. Kurr	2615	

	SEAR	CHED	
Class	Subclass	Date	Examiner
381	13	7/11/2007	JK
455	277.2	7/11/2007	JK
455	278.1	7/11/2007	JK
455	296	7/11/2007	JK
455	309,312	7/25/2007	JK

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
Searched: Noise Suppression in demodulators 455/312,309	7/25/2007	JK			
Searched Japanese References cited in PCT (18 June 2004)	7/11/2007	JK			
·					
·					
	·				